

<b>Notice of References Cited</b>	Application/Control No. 10/672,672	Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0062967	04-2004	Chaix, Jean-Edmond	429/032
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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